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# Contents

## PREFACE

xiii

# 1

## GENERAL INSTRUMENTATION

1

- 1-1. General Description of Instrumentation, 1*
- 1-2. Development of Electronic Instrumentation, 3*
- 1-3. Forms of Electronic Instruments, 4*
- 1-4. Elements of Electronic Instrument Systems, 6*
- 1-5. Overall View of Instrument Systems, 9*

# 2

## THE BASIC METER IN DIRECT-CURRENT MEASUREMENTS

11

- 2-1 The Basic Meter, 11*
- 2-2. Converting the Basic Meter to a Direct-Current Voltmeter, 12*
- 2-3. Converting the Basic Meter to Direct-Current Ranges, 15*
- 2-4. Multiple Direct-Current Voltmeter Ranges, 17*
- 2-5. The Ohmmeter, 17*
- 2-6. The Multimeter, 21*
- 2-7. Input Impedance of Voltmeter, 22*

<b>3</b>	<b>THE BASIC METER IN ALTERNATING-CURRENT MEASUREMENTS</b>	<b>29</b>
	3-1. <i>Rectifier-Type Meter, 29</i>	
	3-2. <i>Computing Alternating-Current Voltage Ranges, 33</i>	
	3-3. <i>Frequency Limitations of Alternating-Current Meters, 34</i>	
	3-4. <i>Dynamometer-Type Alternating-Current Meter, 35</i>	
	3-5. <i>Wattmeters, 36</i>	
	3-6. <i>Moving-Iron-Type Instruments, 38</i>	
	3-7. <i>Summary Classification of Alternating and Direct-Current Meters, 41</i>	
<b>4</b>	<b>COMPARISON MEASUREMENT METHODS</b>	<b>44</b>
	4-1. <i>Comparison versus Deflection Methods, 44</i>	
	4-2. <i>Equal-Deflection Method for Measuring Impedance, 46</i>	
	4-3. <i>Comparison by Null Methods, 47</i>	
	4-4. <i>Null-Type Instruments: Potentiometer and Bridge Types Compared, 47</i>	
	4-5. <i>Potentiometer-Null Voltage Measurement, 49</i>	
	4-6. <i>Calibration of Potentiometer-Null Instruments, 51</i>	
	4-7. <i>Basic Direct-Current (Wheatstone) Bridge, 54</i>	
	4-8. <i>Sensitivity of Unbalanced Bridge, 55</i>	
	4-9. <i>Thévenin Equivalent of Unbalanced Bridge, 56</i>	
	4-10. <i>Error Detection with Unbalanced Bridge, 59</i>	
	4-11. <i>Linearity of Unbalanced Bridge Output, 60</i>	
<b>5</b>	<b>ALTERNATING-CURRENT BRIDGE AND IMPEDANCE MEASUREMENT METHODS</b>	<b>67</b>
	5-1. <i>The General Form of Alternating-Current Bridge, 67</i>	
	5-2. <i>The Maxwell-Bridge Circuit, 68</i>	
	5-3. <i>The Hay-Bridge Circuit, 71</i>	
	5-4. <i>Alternating-Current Null Detectors, 71</i>	
	5-5. <i>Phase-Sensitive Detectors, 74</i>	
<b>6</b>	<b>ELECTRON DEVICES</b>	<b>82</b>
	6-1. <i>Nature of Electrical and Electron Devices, 82</i>	
	6-2. <i>Types of Electron Devices, 82</i>	
	6-3. <i>Diode Characteristics and Properties, 85</i>	
	6-4. <i>Diode Applications, 87</i>	

- 6-5. *Triode Characteristics and Properties, 89*
- 6-6. *Transistor Characteristics, 89*
- 6-7. *Transistor Amplifier Circuit Action, 92*
- 6-8. *The Field-Effect Transistor, 94*
- 6-9. *Electronic Oscillators, 101*
- 6-10. *The Unijunction Transistor, 104*

## 7

### ELECTRONIC VOLTMETERS

116

- 7-1. *The Electronic Voltmeter, 116*
- 7-2. *Types of VTVM Circuits, 116*
- 7-3. *Elementary (Single-Tube) Direct-Current VTVM, 117*
- 7-4. *Resistor-Bridge Arrangement of Single-Tube VTVM, 119*
- 7-5. *Balanced-Bridge Two-Tube Circuit  
(General-Purpose Serive-Type VTVM), 121*
- 7-6. *Electronic Voltmeters for Alternating Current, 123*
- 7-7. *Solid-State Voltmeters, 128*
- 7-8. *High-Sensitivity Direct-Current Measurements, 133*
- 7-9. *Electrometer-Type Direct-Current VTVM, 134*
- 7-10. *Representative Example of Electrometer, 135*
- 7-11. *Modulated Type of Direct-Current VTVM, 137*
- 7-12. *Representative Example of Chopper-Type Direct-Current VTVM, 139*
- 7-13. *VTVM Current Measurements, 140*
- 7-14. *General Summary of Electronic-Voltmeter  
Measurement Ranges, 142*
- 7-15. *Summarized Comparison of Advanced Electric Voltmeters  
and Pico-Ammeters, 142*

## 8

### RECORDING SYSTEMS

151

- 8-1. *Features of Electronic Graphic Recording Systems, 151*
- 8-2. *Types of Transducer Inputs, 154*
- 8-3. *Principle of Self-Balance Operation  
(All-Direct-Current System), 155*
- 8-4. *Analysis of Electronic Direct-Current Self-Balance Circuit, 156*
- 8-5. *Comparing Direct-Current and Alternating-Current  
Input Signals, 157*
- 8-6. *Chopper-Type Input Systems, 158*
- 8-7. *Representative Example of Chopper-Type  
Self-Balancing System, 158*
- 8-8. *Comparison of Electronic Indicator/Recorder Instruments, 163*
- 8-9. *Standardizing Recorder Systems, 164*

- 8-10. *X-Y Recorders, 165*
- 8-11. *Galvanometer (Direct-Writing Oscillograph) Recorders, 166*
- 8-12. *Ink and Inkless Recording Methods, 168*
- 8-13. *Other Types of Permanent Recordings, 169*

## 9

### TRANSDUCERS

172

- 9-1. *Scope of Transducers in Measuring Systems, 172*
- 9-2. *Classes of Transducers, 174*
- 9-3. *The Strain Gage, 179*
- 9-4. *Linear-Variable Differential Transformer, 182*
- 9-5. *Force Measurement Applications (The Accelerometer), 184*
- 9-6. *Semiconductor Photoelectric and Temperature Devices, 185*

## 10

### THE CATHODE-RAY OSCILLOSCOPE

199

- 10-1. *Basic Cathode-Ray Tube Principles, 199*
- 10-2. *Horizontal Time Base (Sweep Voltage), 203*
- 10-3. *Horizontal Deflection by Sine-Wave Voltage, 206*
- 10-4. *The Sweep-Generating Circuit, 206*
- 10-5. *Classes of Cathode-Ray Oscilloscopes, 208*
- 10-6. *Representative General-Purpose Oscilloscope, 211*
- 10-7. *Basic Operation of Oscilloscope (Familiarization Techniques), 213*
- 10-8. *Appraising Oscilloscope Performance, 218*
- 10-9. *Representative Example of Triggered-Sweep Laboratory Oscilloscope, 222*
- 10-10. *Special Features in Oscilloscopes, 225*
- 10-11. *Auxiliary Equipment for Oscilloscopes, 230*
- 10-12. *Summary of Oscilloscope Applications, 233*

## 11

### SIGNAL GENERATORS

239

- 11-1. *Types of Generated Signals, 239*
- 11-2. *Types of Oscillators, 240*
- 11-3. *Representative Audio-Frequency Oscillators (Laboratory Type), 244*
- 11-4. *Square-Wave Generation, 247*
- 11-5. *Commercial Square-Wave Generators, 250*
- 11-6. *Radio-Frequency Signal Generators, 250*

- 11-7. *Representative Service-Type Radio-Frequency Signal Generator, 251*
- 11-8. *Laboratory-Type Radio-Frequency Generator, 253*
- 11-9. *Representative "Standard Signal" Radio-Frequency Generator ("Microvolter"), 254*
- 11-10. *Special-Purpose Signal Generators, 257*

## **12** COMPONENT TEST METHODS 262

- 12-1. *Transistor "Quick-Check," 262*
- 12-2. *Transistor Testers and Analyzers (Curve Tracers), 265*
- 12-3. *Practical Methods for Testing Components, 269*
- 12-4. *RC Checker (Service Type), 270*
- 12-5. *The Q Meter, 273*
- 12-6. *Practical Inductor Checking, 280*
- 12-7. *Direct-Reading Vector Impedance Test, 282*
- 12-8. *Commercial Vector-Impedance Meter, 283*
- 12-9. *Oscillating-Circuit Test for Components, 285*

## **13** INTEGRATED CIRCUITS 287

- 13-1. *Growth of Integrated Circuits, 287*
- 13-2. *Circuit Functions, 289*
- 13-3. *Examples of Digital Integrated Circuits, 290*
- 13-4. *Examples of Linear Integrated Circuits, 295*
- 13-5. *Example of IC Operational Amplifier (IC "Op-Amp"), 297*
- 13-6. *Types of Linear Integrated Circuits, 300*
- 13-7. *Frequency Compensation for Integrated-Circuit Amplifiers, 301*
- 13-8. *Examples of Typical IC Applications, 302*

## **14** UNTUNED-AMPLIFIER TEST METHODS 307

- 14-1. *Untuned Voltage-Amplifier Tests, 307*
- 14-2. *Testing Amplifier Gain and Frequency Response, 308*
- 14-3. *Harmonic-Distortion Testing, 310*
- 14-4. *Intermodulation-Distortion Testing, 313*
- 14-5. *Square-Wave Testing, 316*
- 14-6. *Integrated-Circuit Testing, 317*

- 15 RADIO-FREQUENCY TEST METHODS 321**
- 15-1. *Tuned Radio-Frequency Testing Areas, 321*
  - 15-2. *Measuring Continuous-Wave Radio-Frequency Signals: Direct and Indirect Methods, 322*
  - 15-3. *Impedance Measurements: Radio-Frequency Bridge, 323*
  - 15-4. *Radio-Frequency Voltmeters, 324*
  - 15-5. *Field-Strength and Frequency Tests, 325*
  - 15-6. *Testing with Frequency Meters, 327*
  - 15-7. *Grid-Dip Meter, 332*
  - 15-8. *Sweep-Generator Test Method (Visual Indication of Frequency-Response Characteristics), 336*
  - 15-9. *Frequency Synthesizers, 341*
- 16 NUCLEAR-RADIATION DETECTION INSTRUMENTS 345**
- 16-1. *Nuclear or Ionizing Radiations, 345*
  - 16-2. *Characterizing Strength of Nuclear Radiation, 348*
  - 16-3. *Radiation Hazards, 350*
  - 16-4. *Detection Methods for Nuclear Radiation, 353*
  - 16-5. *Gas-Filled Detectors, 354*
  - 16-6. *Geiger–Mueller Tube-Detector Systems, 357*
  - 16-7. *Ion-Chamber Detectors, 358*
  - 16-8. *Scintillation and Other Detectors, 361*
- 17 DIGITAL INSTRUMENTS 371**
- 17-1. *Digital Instruments, 371*
  - 17-2. *Digital Counting: Logic Elements, 373*
  - 17-3. *Digital Counting versus Computing, 373*
  - 17-4. *Counting Display: Analog versus Digital Display, 374*
  - 17-5. *Binary Counter, 375*
  - 17-6. *Binary and Digital Computation, 377*
  - 17-7. *Digital Frequency and Period Counter, 379*
  - 17-8. *Digital Multimeters, 380*
  - 17-9. *Operating Principles of Digital Voltmeters, 382*
  - 17-10. *Representative Digital Voltmeters, 385*

<b>18</b>	<b>ANALOG COMPUTERS</b>	<b>389</b>
18-1.	<i>Analog versus Digital Computers, 389</i>	
18-2.	<i>Electronic Components of Analog Computers, 392</i>	
18-3.	<i>The Operational Amplifier, 392</i>	
18-4.	<i>Summing Amplifier, 395</i>	
18-5.	<i>Solving Simultaneous Equations, 397</i>	
18-6.	<i>The Integrating Amplifier, 400</i>	
18-7.	<i>Solving a Simple Differential Equation, 400</i>	
18-8.	<i>“Building-Block” Uses of the Operational Amplifier, 403</i>	
18-9.	<i>Computer Operational Modes, 405</i>	
18-10.	<i>Hybrid Computers, 407</i>	
18-11.	<i>Commercial Analog Computer Characteristics, 408</i>	
<b>19</b>	<b>SPECIALIZED INSTRUMENT APPLICATIONS</b>	<b>412</b>
19-1.	<i>Application Fields of Specialized Instruments, 412</i>	
19-2.	<i>Chemical Instrumental Analysis, 414</i>	
19-3.	<i>Hydrogen-Ion Concentration (pH) Determination, 416</i>	
19-4.	<i>Gas Chromatograph, 419</i>	
19-5.	<i>Absorption Spectrophotometer, 423</i>	
19-6.	<i>Biological/Medical Instrumentation, 427</i>	
19-7.	<i>Pollution-Monitoring Instruments, 430</i>	
19-8.	<i>Telemetry and Instrumentation Summary, 432</i>	
<b>A</b>	<b>THÉVENIN’S CIRCUIT THEOREM</b>	<b>441</b>
<b>B</b>	<b>SELECTED BIBLIOGRAPHY</b>	<b>444</b>
<b>C</b>	<b>ANSWERS TO ODD-NUMBERED PROBLEMS</b>	<b>446</b>
	<b>INDEX</b>	<b>449</b>